

Trench gate field-stop IGBT, V series 600 V, 20 A very high speed

Datasheet - production data

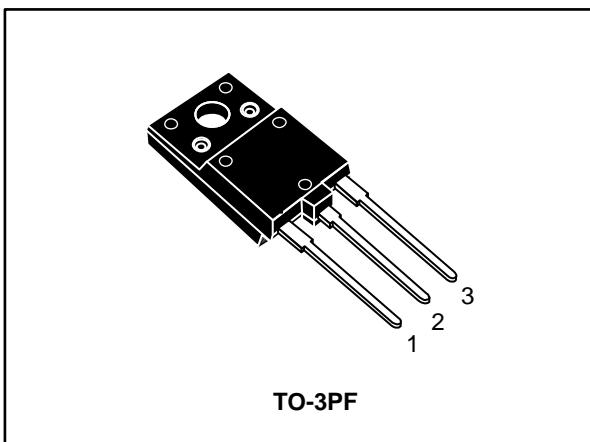
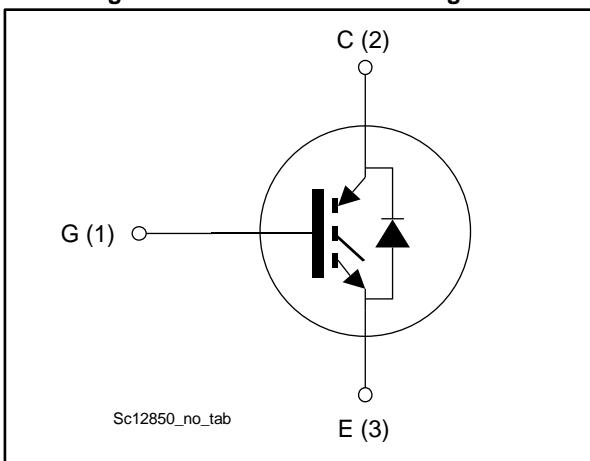


Figure 1: Internal schematic diagram



Features

- Maximum junction temperature: $T_J = 175 \text{ }^{\circ}\text{C}$
- Very high speed switching series
- Tail-less switching off
- $V_{CE(\text{sat})} = 1.8 \text{ V (typ.)} @ I_C = 20 \text{ A}$
- Tight parameters distribution
- Safe paralleling
- Low thermal resistance
- Very fast soft recovery antiparallel diode
- Lead free package

Applications

- Photovoltaic inverters
- Uninterruptible power supply
- Welding
- Power factor correction
- Very high frequency converters

Description

This device is an IGBT developed using an advanced proprietary trench gate field-stop structure. The device is part of the V series IGBTs, which represent an optimum compromise between conduction and switching losses to maximize the efficiency of very high frequency converters. Furthermore, the positive $V_{CE(\text{sat})}$ temperature coefficient and very tight parameter distribution result in safer paralleling operation.

Table 1: Device summary

Order code	Marking	Package	Packing
STGFW20V60DF	G20V60DF	TO-3PF	Tube

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1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V_{CES}	Collector-emitter voltage ($V_{GE} = 0$)	600	V
I_c	Continuous collector current at $T_c = 25^\circ\text{C}$	40	A
	Continuous collector current at $T_c = 100^\circ\text{C}$	20	A
$I_{CP}^{(1)}$	Pulsed collector current	80	A
V_{GE}	Gate-emitter voltage	± 20	V
I_F	Continuous forward current at $T_c = 25^\circ\text{C}$	40	A
	Continuous forward current at $T_c = 100^\circ\text{C}$	20	A
$I_{FP}^{(1)}$	Pulsed forward current	80	A
V_{ISO}	Insulation withstand voltage (RMS) from all three leads to external heat sink ($t = 1 \text{ s}$, $T_c = 25^\circ\text{C}$)	3.5	kV
P_{TOT}	Total dissipation at $T_c = 25^\circ\text{C}$	52	W
T_{STG}	Storage temperature range	-55 to 150	$^\circ\text{C}$
T_J	Operating junction temperature range	-55 to 175	$^\circ\text{C}$

Notes:

(1)Pulse width is limited by maximum junction temperature.

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R_{thJC}	Thermal resistance junction-case IGBT	2.9	$^\circ\text{C}/\text{W}$
R_{thJC}	Thermal resistance junction-case diode	3.4	$^\circ\text{C}/\text{W}$
R_{thJA}	Thermal resistance junction-ambient	50	$^\circ\text{C}/\text{W}$

2 Electrical characteristics

$T_J = 25^\circ\text{C}$ unless otherwise specified

Table 4: Static characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage	$V_{GE} = 0 \text{ V}, I_C = 2 \text{ mA}$	600			V
$V_{CE(\text{sat})}$	Collector-emitter saturation voltage	$V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}$		1.8	2.2	V
		$V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}, T_J = 125^\circ\text{C}$		2.15		
		$V_{GE} = 15 \text{ V}, I_C = 20 \text{ A}, T_J = 175^\circ\text{C}$		2.3		
V_F	Forward on-voltage	$I_F = 20 \text{ A}$		1.7	2.2	V
		$I_F = 20 \text{ A}, T_J = 125^\circ\text{C}$		1.55		
		$I_F = 20 \text{ A}, T_J = 175^\circ\text{C}$		1.3		
$V_{GE(\text{th})}$	Gate threshold voltage	$V_{CE} = V_{GE}, I_C = 1 \text{ mA}$	5	6	7	V
I_{CES}	Collector cut-off current	$V_{GE} = 0 \text{ V}, V_{CE} = 600 \text{ V}$			25	μA
I_{GES}	Gate-emitter leakage current	$V_{CE} = 0 \text{ V}, V_{GE} = \pm 20 \text{ V}$			250	μA

Table 5: Dynamic characteristics

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
C_{ies}	Input capacitance	$V_{CE} = 25 \text{ V}, f = 1 \text{ MHz}, V_{GE} = 0 \text{ V}$	-	2800	-	pF
C_{oes}	Output capacitance		-	110	-	pF
C_{res}	Reverse transfer capacitance		-	64	-	pF
Q_g	Total gate charge	$V_{CC} = 480 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 0 \text{ to } 15 \text{ V}$ (see Figure 28: "Gate charge test circuit")	-	116	-	nC
Q_{ge}	Gate-emitter charge		-	24	-	nC
Q_{gc}	Gate-collector charge		-	50	-	nC

Table 6: IGBT switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 15 \text{ V}$ (see <i>Figure 27: "Test circuit for inductive load switching"</i>)	-	38	-	ns
t_r	Current rise time		-	10	-	ns
$(di/dt)_{on}$	Turn-on current slope		-	1556	-	A/ μs
$t_{d(off)}$	Turn-off-delay time		-	149	-	ns
t_f	Current fall time		-	15	-	ns
$E_{on}^{(1)}$	Turn-on switching energy		-	200	-	μJ
$E_{off}^{(2)}$	Turn-off switching energy		-	130	-	μJ
E_{ts}	Total switching energy		-	330	-	μJ
$t_{d(on)}$	Turn-on delay time	$V_{CE} = 400 \text{ V}, I_C = 20 \text{ A}, V_{GE} = 15 \text{ V}, T_J = 175 \text{ }^\circ\text{C}$ (see <i>Figure 27: "Test circuit for inductive load switching"</i>)	-	37	-	ns
t_r	Current rise time		-	12	-	ns
$(di/dt)_{on}$	Turn-on current slope		-	1340	-	A/ μs
$t_{d(off)}$	Turn-off-delay time		-	150	-	ns
t_f	Current fall time		-	23	-	ns
$E_{on}^{(1)}$	Turn-on switching energy		-	430	-	μJ
$E_{off}^{(2)}$	Turn-off switching energy		-	210	-	μJ
E_{ts}	Total switching energy		-	640	-	μJ

Notes:

(1) Including the reverse recovery of the diode.

(2) Including the tail of the collector current.

Table 7: Diode switching characteristics (inductive load)

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
t_{rr}	Reverse recovery time	$I_F = 20 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}, di/dt = 1000 \text{ A}/\mu\text{s}$ (see <i>Figure 27: "Test circuit for inductive load switching"</i>)	-	40	-	ns
Q_{rr}	Reverse recovery charge		-	320	-	nC
I_{rrm}	Reverse recovery current		-	16	-	A
dI_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	910	-	A/ μs
E_{rr}	Reverse recovery energy		-	115	-	μJ
t_{rr}	Reverse recovery time		-	72	-	ns
Q_{rr}	Reverse recovery charge	$I_F = 20 \text{ A}, V_R = 400 \text{ V}, V_{GE} = 15 \text{ V}, T_J = 175 \text{ }^\circ\text{C}, di/dt = 1000 \text{ A}/\mu\text{s}$ (see <i>Figure 27: "Test circuit for inductive load switching"</i>)	-	930	-	nC
I_{rrm}	Reverse recovery current		-	26	-	A
dI_{rr}/dt	Peak rate of fall of reverse recovery current during t_b		-	530	-	A/ μs
E_{rr}	Reverse recovery energy		-	307	-	μJ

2.1 Electrical characteristics curves

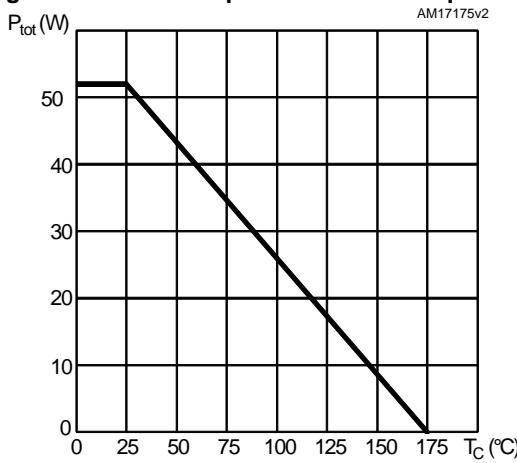
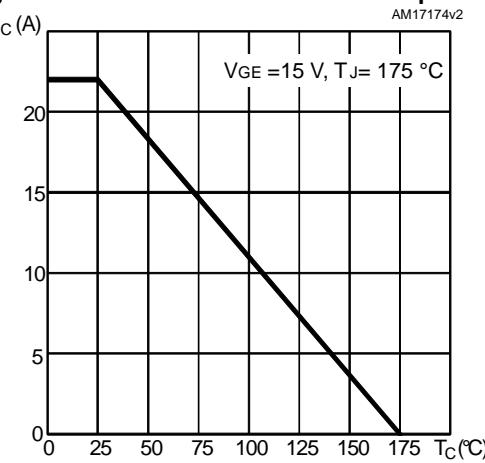
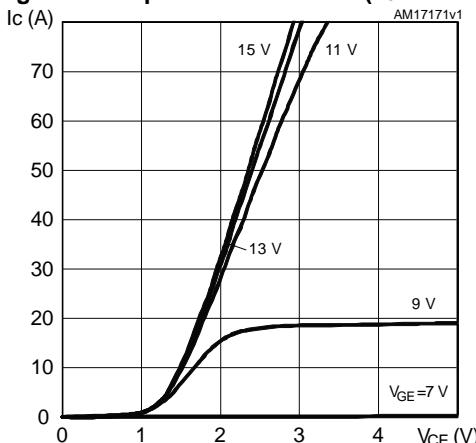
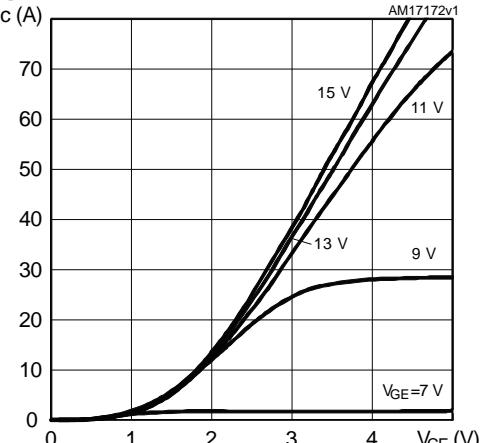
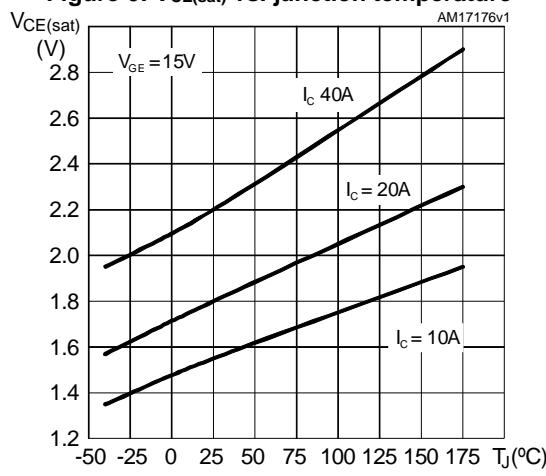
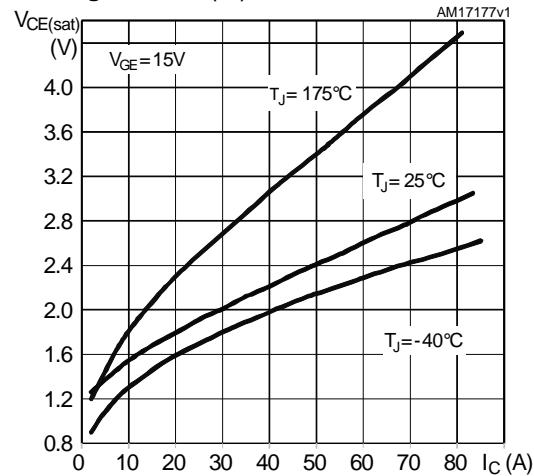
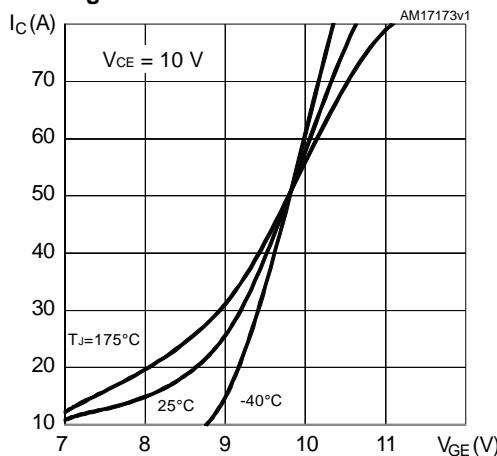
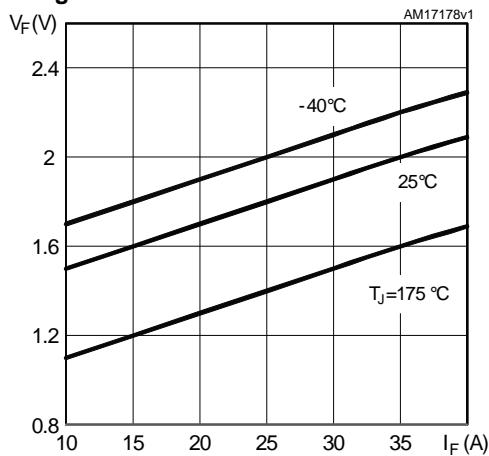
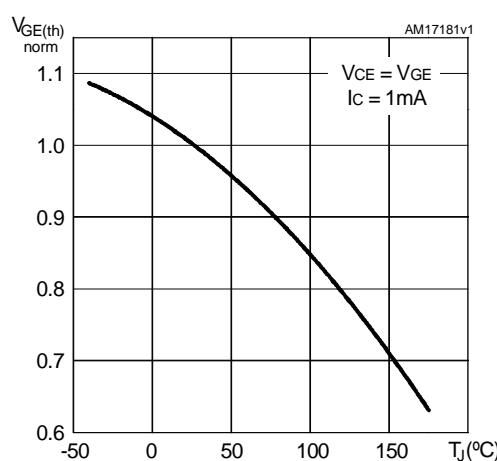
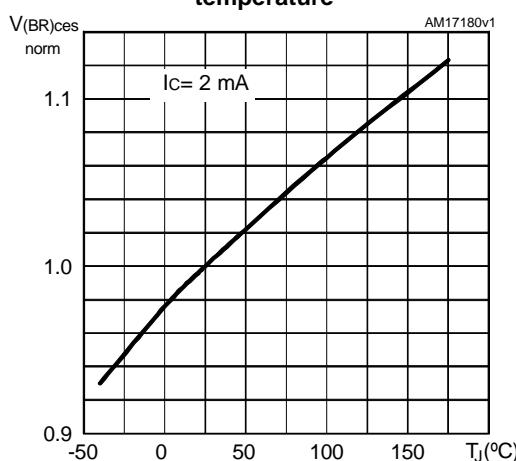
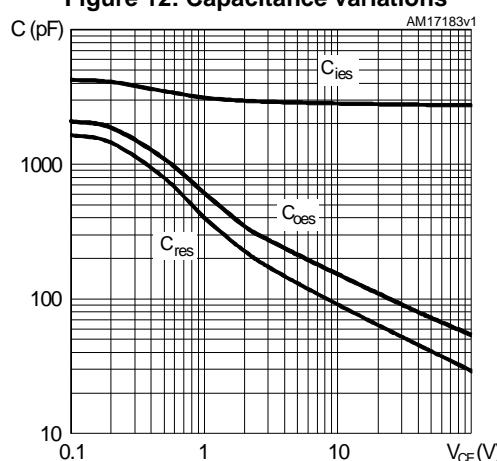
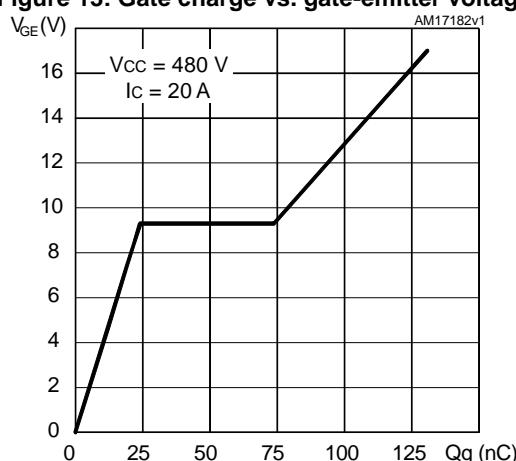
Figure 2: Power dissipation vs. case temperature**Figure 3: Collector current vs. case temperature****Figure 4: Output characteristics ($T_J = 25^\circ\text{C}$)****Figure 5: Output characteristics ($T_J = 175^\circ\text{C}$)****Figure 6: $V_{CE(\text{sat})}$ vs. junction temperature****Figure 7: $V_{CE(\text{sat})}$ vs. collector current**

Figure 8: Transfer characteristics**Figure 9: Diode V_F vs. forward current****Figure 10: Normalized $V_{GE(\text{th})}$ vs. junction temperature****Figure 11: Normalized $V_{(BR)CES}$ vs. junction temperature****Figure 12: Capacitance variations****Figure 13: Gate charge vs. gate-emitter voltage**

Electrical characteristics

STGFW20V60DF

Figure 14: Switching energy vs. collector current

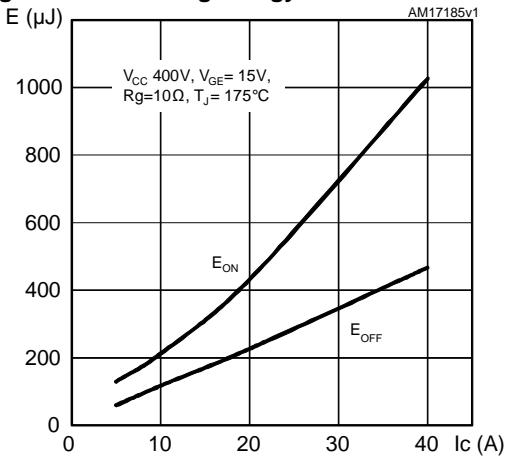


Figure 15: Switching energy vs. gate resistance

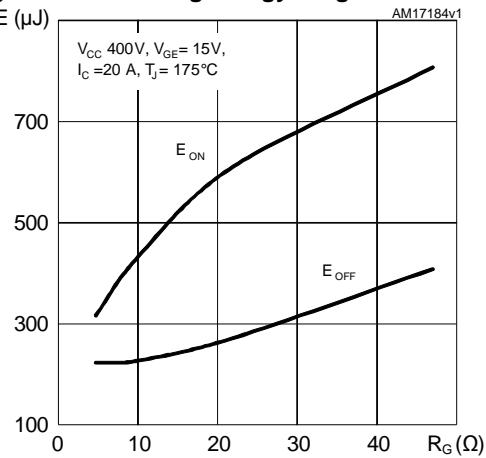


Figure 16: Switching energy vs. junction temperature

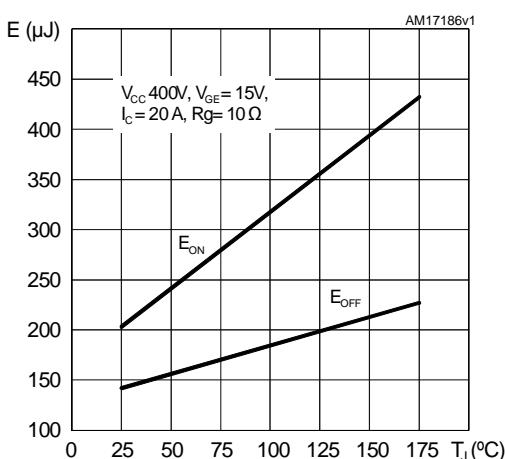


Figure 17: Switching energy vs. collector emitter voltage

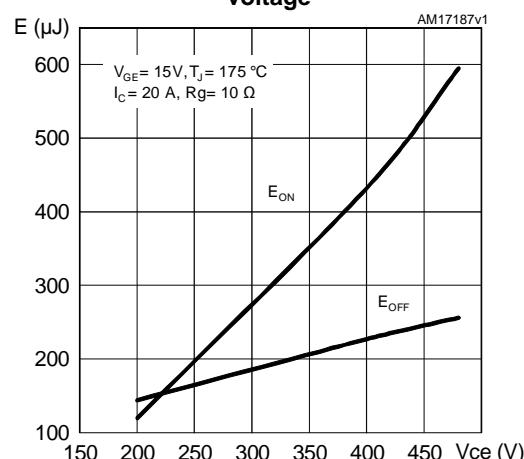


Figure 18: Switching times vs. collector current

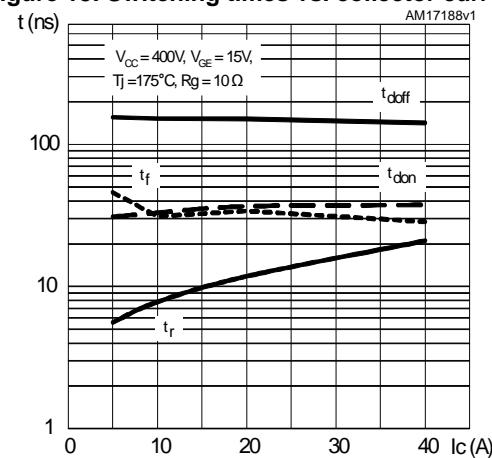


Figure 19: Switching times vs. gate resistance

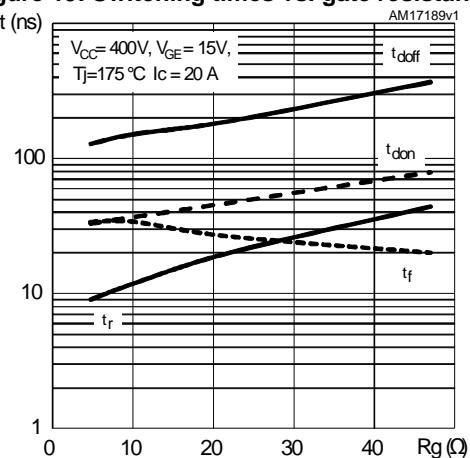
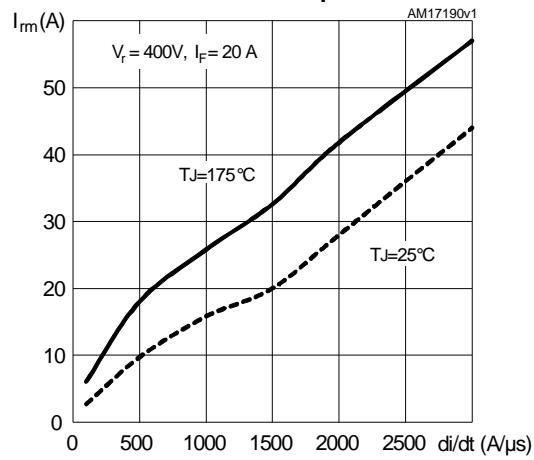
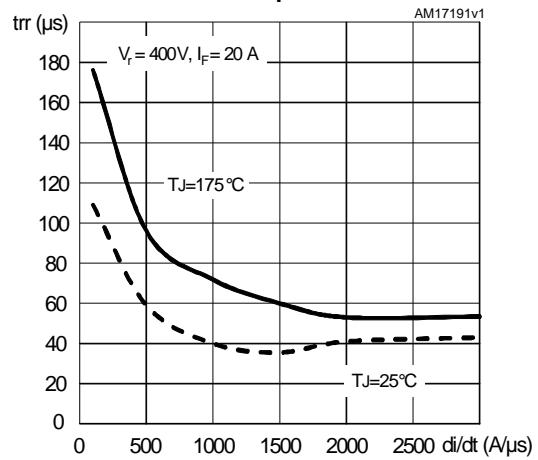
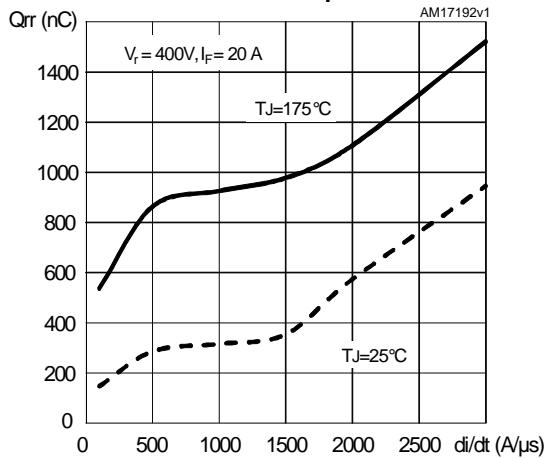
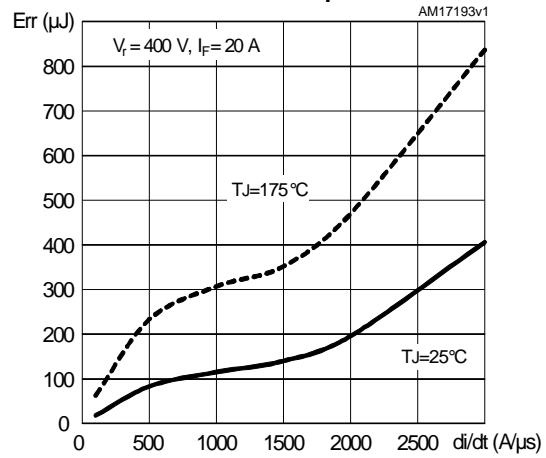
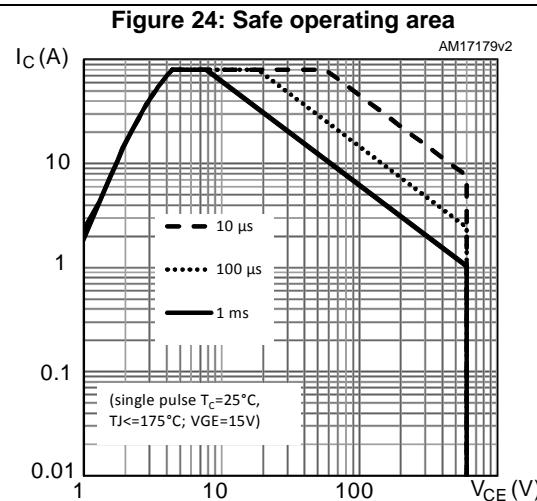
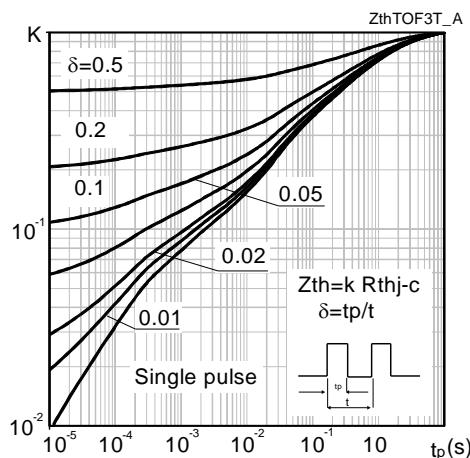
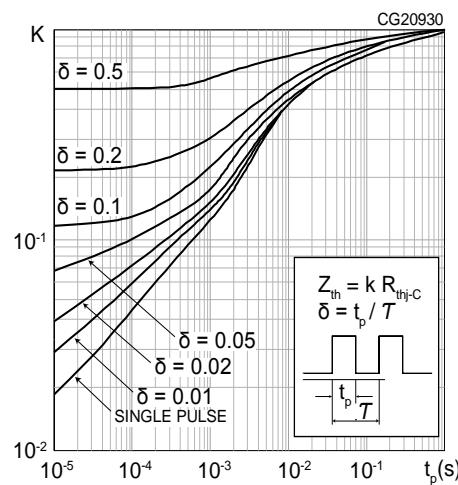
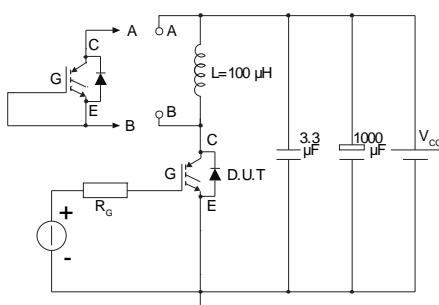


Figure 20: Reverse recovery current vs. diode current slope**Figure 21: Reverse recovery time vs. diode current slope****Figure 22: Reverse recovery charge vs. diode current slope****Figure 23: Reverse recovery energy vs. diode current slope**

**Figure 25: Thermal impedance for IGBT****Figure 26: Thermal impedance for diode**

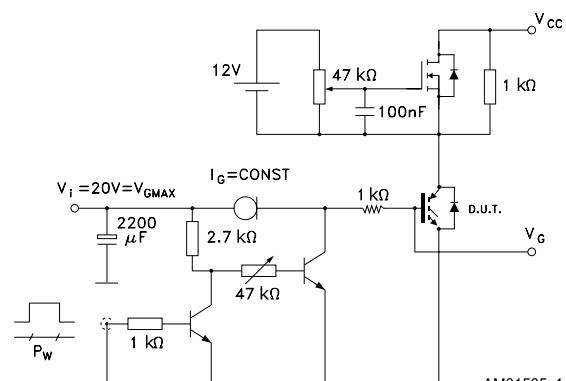
3 Test circuits

Figure 27: Test circuit for inductive load switching



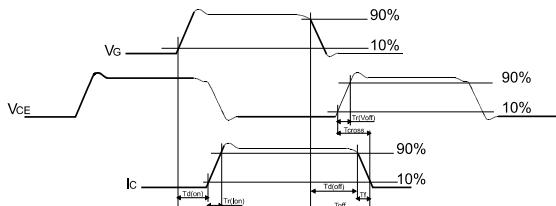
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Figure 28: Gate charge test circuit



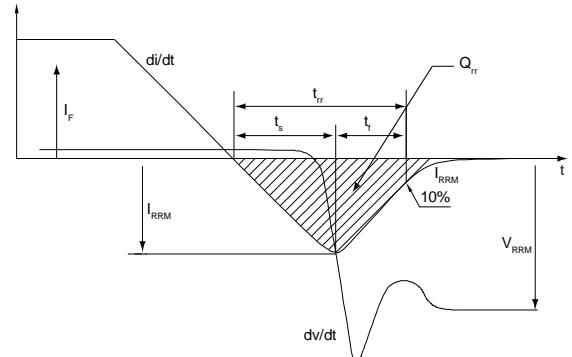
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Figure 29: Switching waveform



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Figure 30: Diode reverse recovery waveform



AM01507v1

4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com.
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4.1 TO-3PF package information

Figure 31: TO-3PF package outline

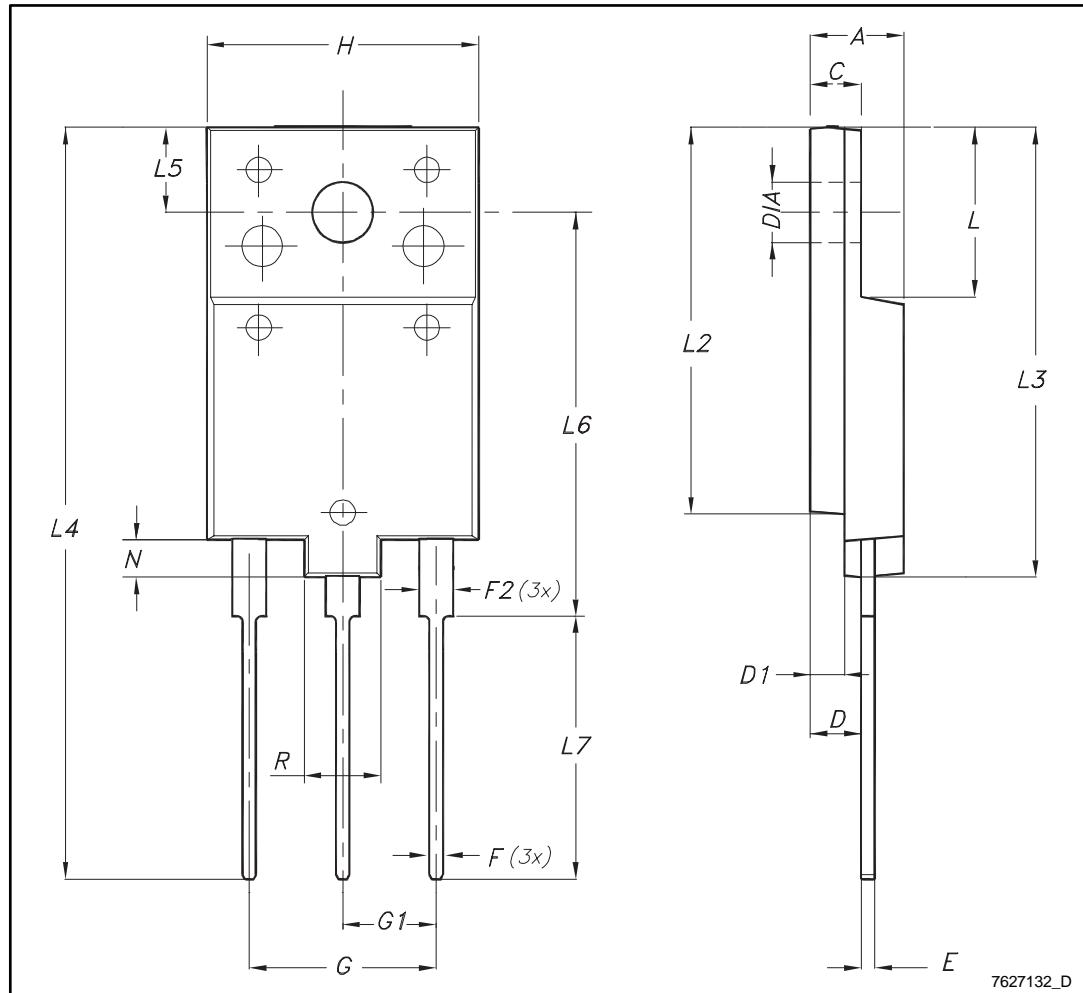


Table 8: TO-3PF mechanical data

Dim.	mm		
	Min.	Typ.	Max.
A	5.30		5.70
C	2.80		3.20
D	3.10		3.50
D1	1.80		2.20
E	0.80		1.10
F	0.65		0.95
F2	1.80		2.20
G	10.30		11.50
G1		5.45	
H	15.30		15.70
L	9.80	10	10.20
L2	22.80		23.20
L3	26.30		26.70
L4	43.20		44.40
L5	4.30		4.70
L6	24.30		24.70
L7	14.60		15
N	1.80		2.20
R	3.80		4.20
Dia	3.40		3.80

5 Revision history

Table 9: Document revision history

Date	Revision	Changes
28-Mar-2014	1	Initial release
14-Feb-2017	2	Updated Table 1: "Device summary" . Minor text changes

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